

Electronic Supplementary Information to:

The Formation and Characterisation of Ultra-Thin Films Containing Ag Nanoparticles

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1. Atomic Force Microscope

The average size of Ag nanoparticles on the annealed sample (after Step 3) can be determined from AFM images. A typical AFM image and height profile is presented in fig S1.

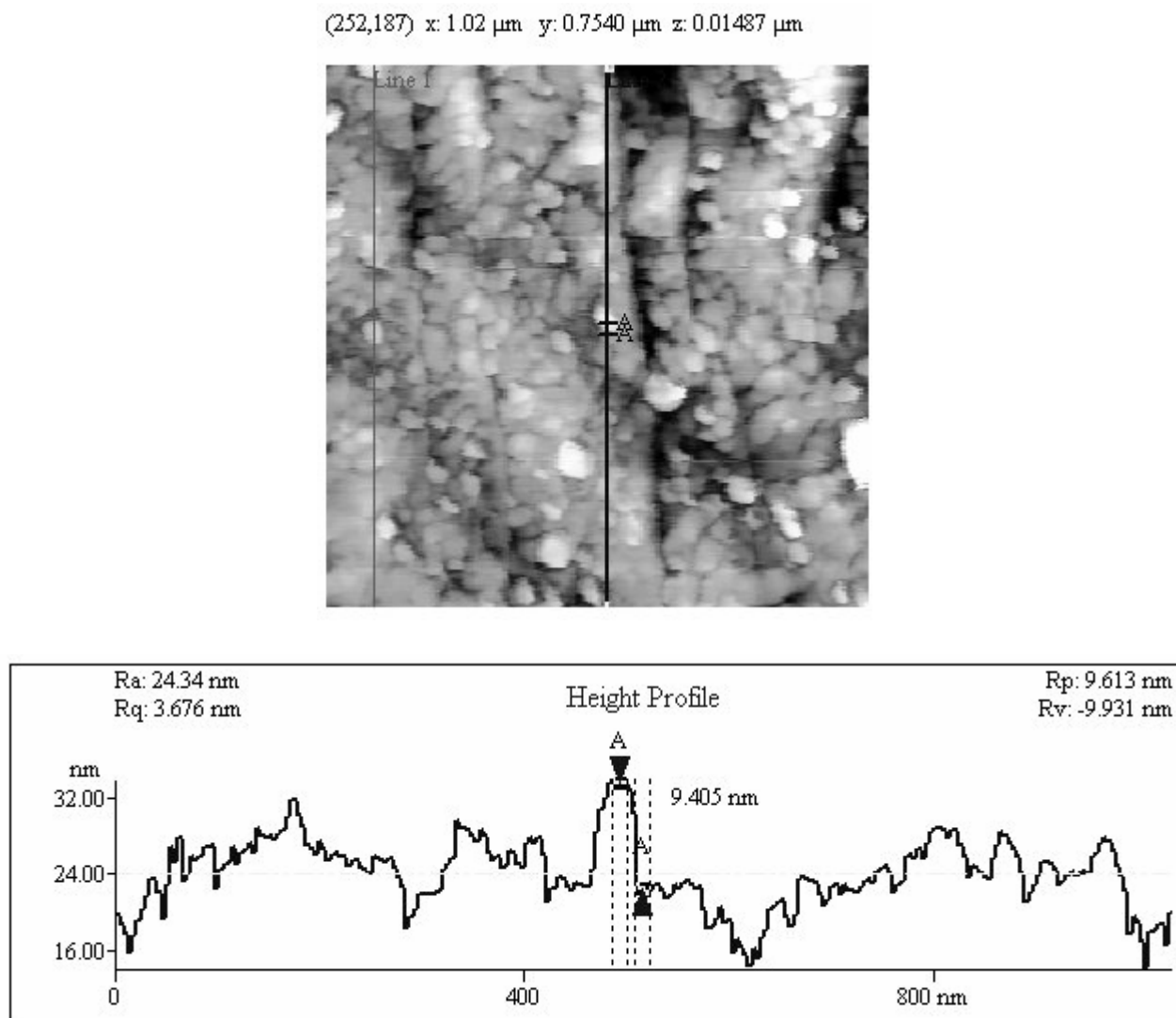


Fig. S1. A typical AFM image of a sample after Step 3 (annealed 120°C for 2h) and a height profile for the calculation of the size of Ag nanoparticles.

2. Field Emission Auger Electron Microscope

To confirm the homogenous nature of the film, both the maps of N and Si peak intensities of pure DIAMO coated sample (after annealing at 120°C for 2h) were measured and they are presented in Fig. S2.

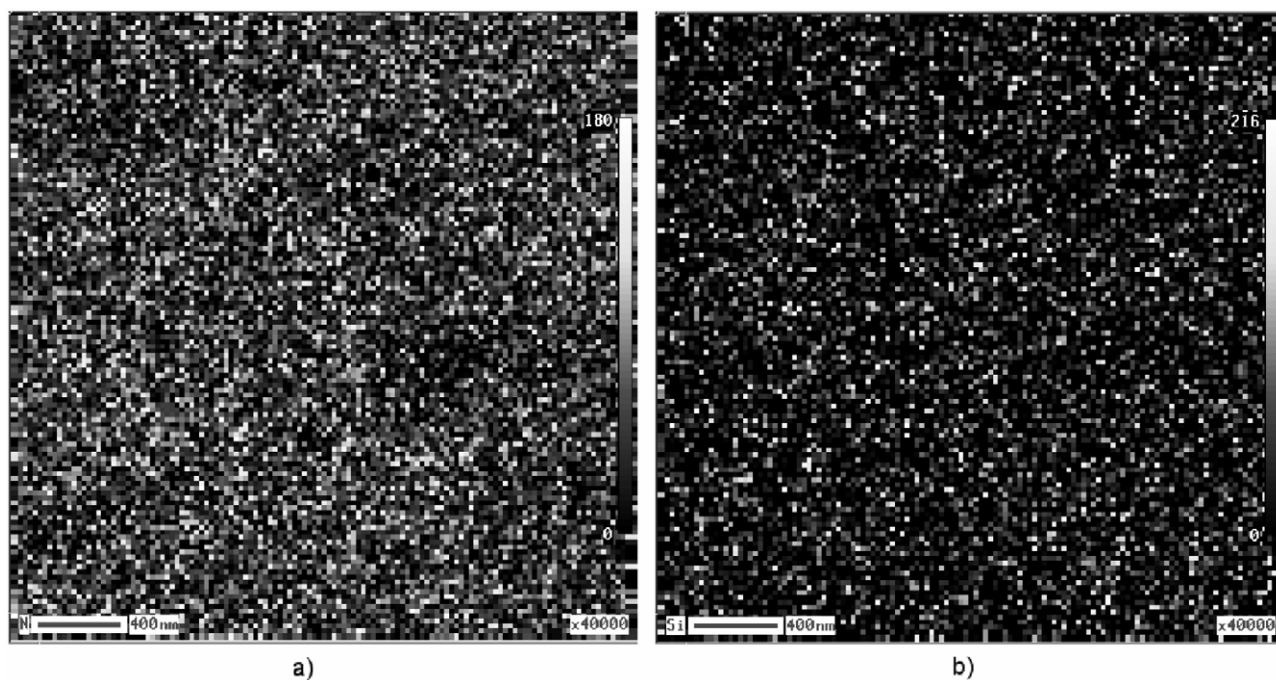


Fig. S2. Maps of peak intensities of a pure DIAMO coated sample (after Step 1 plus annealing at 120°C for 2h): a) map of N peak intensity and b) map of Si peak intensity.